



## Reliability Data – MTTF/FIT Report

Product Information			
Part Number		AL5887JAZW52-13	
Circuit design	LED	Package type	W-QFN6060-52/SWP
Wafer version	AD08070547D0	Assembly site	GTK
Fab site	Dongbu HiTek	Test site	GTK
Process	BCD	Report date	2025-02-03

### Test result:

Test	Test Conditions	Equivalent Device Hours(EDH)	Sample Size	Defect
HTOL	TJ>125°C, Vcc 100%	56236968.9	3025	0

### Reliability Calculations:

Activation Energy (eV): 0.7 electron-Volts		
Die Junction Temperature: 55 °C		
Confidence Level	MTTF (Hours)	FITs
60%	6.14E 07	16.29
90%	2.44E 07	40.94

### Remark:

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